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L2	1	L1 and @ad<"20010223"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/29 11:38
L3	7	embroidery and rule and knowledge and base	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/29 11:37
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L5	3961	"needle point"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/29 11:39
L6	5	5 and knowledge and base and rule	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/04/29 11:40
L7	5	L6 and @ad<"20010223"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/29 11:49
L8	549	706/47	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/29 11:49
L9	476	l8 and @ad<"20010223"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/29 11:56
L10	45	sewing and design and rule and knowledge and base	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/29 12:00

L11	30	L10 and @ad<"20010223"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/29 12:01
L12	262	fabric and design and rule and knowledge and base and computer	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/29 12:00
L13	122	L12 and @ad<"20010223"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/29 12:05
L14	585	706/46	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/29 12:05
L15	512	L14 and @ad<"20010223"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/29 12:11
L16	333	706/14	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/29 12:10
L17	294	L16 and @ad<"20010223"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/29 12:11
S35	6	embroidery and design and rule and knowledge and base	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/29 06:55
S36	5	S35 and @ad<"20020222"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/29 11:36



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Pages:692 - 695

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Image Processing And Its Applications, 1999. Seventh International Conference on (Conf. Publ. No. 465) , Volume: 1 , 13-15 July 1999

Pages:429 - 434 vol.1

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